Substitute Form PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 07977-103003

Application No. 10/811,920

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**Corrected Information Disclosure Statement** by Applicant (Use several sheets if necessary)

(37 CFR §1.98(b))

**Applicant** Hongyong Zhang

Filing Date March 30, 2004 Group Art Unit

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
200	AA	5,148,301	09/1992	Sawatsubashi, et al.		п т прргоргась	
1	AB	5,179,460	01/1993	Hinata, et al.			
<del>                                     </del>	AC	5,200,847	04/1993	Mawatari, et al.			
	AD	5,323,042	06/1994	H. Matsumoto			
	AE	5,396,356	03/1995	Fukuchi			
	AF	5,517,344	05/1996	Hu, et al.	1		
	AG	5,537,235	07/1996	Ishihara, et al.			
	AH	5,572,046	11/1996	Y. Takemura			
	AI	5,598,283	01/1997	Fujii, et al.			
	AJ	5,619,358	04/1997	Tanaka, et al.			
	AK	5,621,553	04/1997	Nishiguchi, et al.			
	AL	5,684,547	11/4/97	Park, et al.			
	AM	5,684,555	11/1997	Shiba, et al.			
	AN	5,691,793	11/1997	Watanabe, et al.			
	AO	5,706,069	01/1998	Hermens, et al.			
	AP	5,745,208	04/1998	Grupp, et al.			
	AQ	5,798,812	08/1998	Nishiki, et al.			
	AR	5,929,959	07/1999	Iida, et al.			
	AS	5,995,189	11/1999	H. Zhang			
	AT	6,011,607	01/2000	Yamazaki, et al.			
	AU	6,037,005	03/2000	Moshrefzadeh, et al.			
	AV	6,055,034	04/2000	Zhang, et al.			
V	AW	6,072,556	06/2000	Hirakata, et al.			
	AX						

Examiner Signature	Date Considered			
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(Use several sheets if necessary)		Filing Date March 30, 2004	Group Art Unit Unknown	

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or				lation
Initial	ID_	Number	Date	Patent Office	Class	Subclass	Yes	No
200	AY	0 612 102 A2	08/1994	EPO				
280	AZ	JP 04-97321	03/1992	Japan				
200	ВА	JP 06-51332	02/1994	Japan				
>00	ВВ	JP 06-51332	02/1994	Japan			<u> </u>	
200	ВС	JP 10-198292	07/1998	Japan				
200	BD	JP 62-229234	10/1987	Japan				
	BE-						<u> </u>	

	Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner Initial	Desig. ID	Document				
	BF					
	BG					
	ВН					
	BI					

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